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| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination STEINMEYER ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 |
| U.S. PATENT DOCUMENTS | | | | |

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------------|----------------|
| * | A | US-6,124,276 | 09-2000 | Miyamoto et al. | 514/167 |
| * | B | US-6,479,538 | 11-2002 | Reddy, Satyanarayana G. | 514/451 |
| * | C | US-6,127,559 | 10-2000 | DeLuca et al. | 552/653 |
| * | D | US-5,945,410 | 08-1999 | DeLuca et al. | 514/167 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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